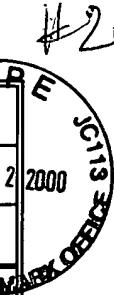


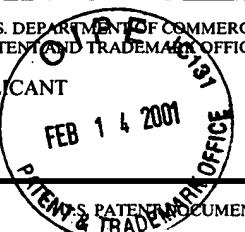
1/2  
09/556491  
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET MI22-1422	SERIAL NO. Unknown	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Scott E. Moore et al.		
					FILING DATE Filed Herewith	GROUP Unknown	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WB	AA	5,755,614	05/26/98	Adams et al.			
WB	AB	5,664,990	09/09/97	Adams et al.			
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AF						No
	AG						
	AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
WB	AJ			<a href="http://www.intratechnology.com/html/sensors.htm">http://www.intratechnology.com/html/sensors.htm</a> , Intra Technology, Sensors, 03/25/99, 2 pages			
WB	AJ			<a href="http://www.ftsinc.com/complete/analite/analite.htm">http://www.ftsinc.com/complete/analite/analite.htm</a> , FTS, Analite-SDI Turbidity Sensor, 03/25/99, 1 page			
WB	AK			<a href="http://www.customsensors.com/optimax.htm">http://www.customsensors.com/optimax.htm</a> , Custom Sensors & Technology, OptiMax 6000 Series Process Photometric Analyzers, 03/25/99, 2 pages			
WB	AL			<a href="http://www.reflectronics.com/reflectronics_inc_contents.htm">http://www.reflectronics.com/reflectronics_inc_contents.htm</a> , Reflectronics, Inc., Fiber Optic Backscatter Sensor, 03/25/99, 1 page			
WB	AM			<a href="http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st">http://www.honeywell.com/sensing/prodinfo/turbidity/technical/turbidity.st</a> , Gary O'Brien, Honeywell, Turbidity Sensor for Electromechanical Dishwasher Control, 1998-1999, 11 pages			
WB	AT			<a href="http://www.impomag.com/O_automat/10970064.htm">http://www.impomag.com/O_automat/10970064.htm</a> , ABB Instrumentation, The Stockroom, Photodiode Sensor, 1999, 1 page			
EXAMINER		Willie Berry, Jr.		DATE CONSIDERED		1/23/02	
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1422	SERIAL NO. 09/556,491	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Scott E. Moore et al.	JUN 12 2000	
					FILING DATE April 21, 2000	GROUP Unknown	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
	AF						No
	AG						
	AH						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
WB	AI		"The Science and Engineering of Micronielectronic Fabrication"; Campbell, Stephen A.; Oxford University Press; 1996; pp. 253-257.				
	AI						
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	AL						
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	AT						
EXAMINER			DATE CONSIDERED				
Willie Berry, Jr.			1/23/02				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1422	SERIAL NO. 09/556,491		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Scott E. Moore et al.			
				FILING DATE April 21, 2000	GROUP Unknown		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
WB	AA	5,836,805	11/1998	Obeng			
WB	AB	6,066,030	5/2000	Uzoh			
WB	AC	6,077,147	6/2000	Yang et al.			
WB	AD	6,048,256	4/2000	Obeng et al.			
	AE						
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	AI						
	AJ						
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	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AM						Yes
	AN						No
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER Willie Berry, Jr.				DATE CONSIDERED 1/23/02			
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Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				ATTY. DOCKET NO. MI22-1422		SERIAL NO. 09/556,491		
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				FILING DATE April 21, 2000		GROUP 3723		
U.S. PATENT & TRADEMARK DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
WB	AA	5,653,624	8/5/97	Ishikawa et al.				
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	AF							
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	AH							
	AI							
	AJ							
	AK							
	AL							
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
	AO							
	AP							
	AQ							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
	AS							
	AT							
EXAMINER <i>Willie Berry, Jr.</i>				DATE CONSIDERED <i>1/23/02</i>				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

Form PTO-140		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1422	SERIAL NO. 09/556,491
 MAY 07 2001		LIST OF ARTS CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Scott E. Moore et al.	
					FILING DATE April 21, 2000	GROUP 3723
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*Examiner Initial		Document Number	Date	Name	Class	Subclass
WB	AA	5,718,620	2/17/98	Tanaka et al.		
WB	AB	5,885,134	3/23/99	Shibata		
WB	AC	6,099,386	8/8/00	Tsai et al.		
WB	AD	6,159,082	12/12/00	Sugiyama et al.		
WB	AE	6,165,048	12/26/00	Russ et al.		
WB	AF	6,183,352 B1	2/6/01	Kurisawa		
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
FOREIGN PATENT DOCUMENTS						
		Document Number	Date	Country	Class	Subclass
Translation						
Yes      No						
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	AN					
	AO					
	AP					
	AQ					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
	AR					
	AS			RECEIVED		
	AT			MAY 15 2001		
TECHNOLOGY CENTER R3700						
EXAMINER Willie Berry, Jr.			DATE CONSIDERED 1/23/02			
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